

REPORT

For

Dallas Semiconductor Corp.

4401 S. Beltwood Parkway Dallas, TX 75244-3292 U.S.A

Date: March 2, 2007

Report No.: 8680-1

Revision No.: 0 Project No.: 8680

Equipment: Controllers

Model No.: DS1921G, DS1922L, DS1922T, DS1923

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Client: Dallas Semiconductors Corp. Date Issued: March 2, 2007 Report No.:8680-1 Project No.: 8680 Revision No.: 0

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Date Issued: March 2, 2007

Project No.: 8680

TEST REPORT					
Report reference No:	8680-1				
Date of issue:					
Testing laboratory:	LabTest Certification Inc.				
Address:	3133 – 20800 Westminster Hwy., Richmond, BC.				
Testing location:					
Applicant:	Dallas Semiconductors Corp.				
Address:	4401 S. Beltwood Parkway Dallas, TX 75244-3292 U.S.A				
Standard:	IS EN 60529/A1:2003 – Degrees of Protection Provided by Enclosures (IP code)				
Test Report Form No:	8680-1				
Number of pages (Report):	11				
Number of pages (Attachments):	None				
Compiled by:	Approved by: Kaunde Shillon				
(+ signature) Sandeep Bha	ayana (+ signature) Kavinder Dhillon				

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Type of test object....: Semiconductors

Model and/or type reference DS1921G, DS1922L, DS1922T, DS1923

Rating(s) IP56

Trademark: N/A

Responsible Manufacturer..... N/A Factory Locations: N/A

Test item particulars:

Connection to the supply: N/A Operating condition N/A Equipment mobility: N/A Protection class: N/A Operating environment: N/A

Possible test case verdicts:

- test case does not apply to the test object .. : N/A-Not Applicable

- test object does meet the requirement......: P-Pass

test object does not meet the requirement..: F-Fail

Attachments:

None

General remarks:

"(see remark #)" refers to a remark appended to the report.

"(see appended table)" refers to a table appended to the report.

Throughout this report a period is used as the decimal separator.

The test results presented in this report relate only to the object tested.

This report shall not be reproduced except in full without the written approval of the testing laboratory.

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Client: Dallas Semiconductors Corp.

Prov. Lab. 2, 2007

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Test Section

Test No.	Tests	EN 60529:1992 (Clauses)	Verdict
1	Dust Test- IP5X	13.4	Р
2	Water Spray Test with 12.5mm nozzle- IPX6	14.2.6	Р

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IP5X-Dust Test:

Project No.: 8680 Date: Feb. 19, 2007 Equipment ID#: 113 File No.: 8680 DS1921G, DS1922L, Model No(s): DS1922T, DS1923 Serial No(s): N/A Sample No.: 354444,354447,354450,354451 Tested By: Sandeep Bhayana **Print** Signature Reviewed by: Kavinder Dhillon **Print** Signature

> **METHOD** (IS EN 60529/A1:2003) (Clause 13.4)

13.4 Dust test for first characteristic numerals 5 and 6

The test is made using a dust chamber incorporating the basic principles shown in Figure 2 whereby the powder circulation pump may be replaced by other means suitable to maintain the talcum powder in suspension in a closed test chamber. The talcum powder used shall be able to pass through a square-meshed sieve the nominal wire diameter of which is 50 um and the nominal width of a gap between wires 75 µm. The amount of talcum powder to be used is 2 kg per cubic metre of the test chamber volume. It shall not have been used for more than 20 tests.

NOTE Health and safety regulations should be observed in selecting the type of talcum powder and its use.

Enclosures are of necessity in one of two categories:

Category 1: Enclosures where the normal working cycle of the equipment causes reductions in air pressure within the enclosure below that of the surrounding air, e.g., due to thermal cycling effects.

Category 2: Enclosures where no pressure difference relative to the surrounding air is present.

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Category 2 enclosures:

The enclosure under test is supported in its normal operating position inside the test chamber, but is not connected to a vacuum pump. Any drain-hole normally open shall be left open for the duration of the test. The test shall be continued for a period of 8 h.

13.5.2 Acceptance conditions for first characteristic numeral 5

The protection is satisfactory if, on inspection, talcum powder has not accumulated in a quantity or location such that, as with any other kind of dust, it could interfere with the correct operation of the equipment or impair safety. Except for special cases to be clearly specified in the relevant product standard, no dust shall deposit where it could lead to tracking along the creepage distances.

Observation: No dust observed inside the controllers.

Final Result: P

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Client: Dallas Semiconductors Corp.

IPX6-Water Spray Test:

Project No.:	8680	Date:	Feb.19,2007
Equipment ID#:	139	File No.:	8680
Model No(s):	DS1921G, DS1922L, DS1922T, DS1923		
Serial No(s):	N/A	Sample No.:	354444,354447,354450,354451
Tested By:	Sandeep Bhayana		Sprages.
	Print		Signature
Reviewed by:	Kavinder Dhillon		Kavida Shellon

METHOD (IS EN 60529/A1:2003) (Clause 14.2.6)

14.2.6 Test for second characteristic numeral 6 with the 12,5 mm nozzle

The test is made by spraying the enclosure from all practicable directions with a stream of water from a standard test nozzle as shown in Figure 6.

The conditions to be observed are as follows:

- internal diameter of the nozzle: 12,5 mm;
- delivery rate: 100 l/min ± 5 %;
- water pressure: to be adjusted to achieve the specified delivery rate;
- core of the substantial stream: circle of approximately 120 mm diameter at 2,5 m distance from nozzle;
- test duration per square metre of enclosure surface area likely to be sprayed: 1 min;
- minimum test duration: 3 min;
- distance from nozzle to enclosure surface: between 2.5 m and 3 m.

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14.3 Acceptance conditions

After testing in accordance with the appropriate requirements of 14.2.1 to 14.2.8 the enclosure shall be inspected for ingress of water.

It is the responsibility of the relevant Technical Committee to specify the amount of water which may be allowed to enter the enclosure and the details of a dielectric strength test, if any.

In general, if any water has entered, it shall not:

- be sufficient to interfere with the correct operation of the equipment or impair safety;
- deposit on insulation parts where it could lead to tracking along the creepage distances;
- reach live parts or windings not designed to operate when wet;
- accumulate near the cable end or enter the cable if any.

If the enclosure is provided with drain-holes, it should be proved by inspection that any water which enters does not accumulate and that it drains away without doing any harm to the equipment.

For enclosures without drain-holes, the relevant product standard shall specify the acceptance conditions if water can accumulate to reach live parts.

Observation: No ingress of water observed inside the controllers.

Final Result: P

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Picture-1. - Dust Test Setup (IP5X)

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Paragraphy 2, 2007

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Picture-2. – Water Spray Test Setup (IPX6)

END OF TEST REPORT